


<b>Search Notes</b> 	<b>Application/Control No.</b> 10552837	<b>Applicant(s)/Patent Under Reexamination</b> BEYER ET AL.
	<b>Examiner</b> CHUN CHEUNG	<b>Art Unit</b> 3728

SEARCHED			
Class	Subclass	Date	Examiner
206	321	3/5/2009	CC
428	43	3/6/2009	CC
206	83.5, 442, 216, 223	3/9/2009	CC
53	443, 447, 528	3/9/2009	CC

SEARCH NOTES		
Search Notes	Date	Examiner
Plus Search	3/5/2009	CC
Inventor Search	3/5/2009	CC
East Search	3/5/2009	CC
Backward/Forward Search	3/5/2009	CC
Spoke to primary (Luan Bui) for search	3/6/2009	CC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/CHUN CHEUNG/  
Examiner, Art Unit 3728